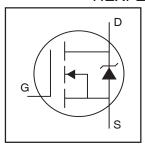
# International Rectifier

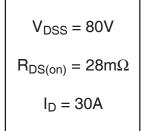
# IRLR2908PbFIRLU2908PbF

HEXFET® Power MOSFET

#### **Features**

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Timax
- Lead-Free

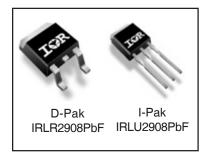




## **Description**

This HEXFET ® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this HEXFET power MOSFET are a 175°C junction operating temperature, low RθJC, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in a wide variety of applications.

The D-Pak is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU series) is for through-hole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.



### **Absolute Maximum Ratings**

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	39	Α
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (See Fig. 9)	28	*
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	30	*
I <sub>DM</sub>	Pulsed Drain Current ①	150	*
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	120	W
	Linear Derating Factor	0.77	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 16	V
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally Limited) ②	180	mJ
E <sub>AS</sub> (tested)	Single Pulse Avalanche Energy Tested Value ②	250	•
I <sub>AR</sub>	Avalanche Current ①	See Fig.12a,12b,15,16	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ®		mJ
dv/dt	Peak Diode Recovery dv/dt ③	2.3	V/ns
$T_J$	Operating Junction and	-55 to + 175	°C
T <sub>STG</sub>	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.3	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) ®		40	
$R_{\theta JA}$	Junction-to-Ambient		110	

## IRLR/U2908PbF

International **IOR** Rectifier

## Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	80			٧	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.085		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		22.5	28	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 23A ④
			25	30	1	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 20A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0		2.5	٧	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
gfs	Forward Transconductance	35			S	$V_{DS} = 25V, I_{D} = 23A$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 80V, V_{GS} = 0V$
				250	1	$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			200	nA	V <sub>GS</sub> = 16V
	Gate-to-Source Reverse Leakage			-200	1	V <sub>GS</sub> = -16V
$Q_g$	Total Gate Charge		22	33	nC	I <sub>D</sub> = 23A
Q <sub>gs</sub>	Gate-to-Source Charge		6.0	9.1	Ī	$V_{DS} = 64V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		11	17	Ī	$V_{GS} = 4.5V$
t <sub>d(on)</sub>	Turn-On Delay Time		12		ns	$V_{DD} = 40V$
t <sub>r</sub>	Rise Time		95		Ī	$I_D = 23A$
t <sub>d(off)</sub>	Turn-Off Delay Time		36		Ī	$R_G = 8.3\Omega$
t <sub>f</sub>	Fall Time		55		Ī	V <sub>GS</sub> = 4.5V ④
L <sub>D</sub>	Internal Drain Inductance		4.5		nH	Between lead,
						6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		7.5		Ī	from package
						and center of die contact
C <sub>iss</sub>	Input Capacitance		1890		pF	$V_{GS} = 0V$
Coss	Output Capacitance		260		Ī	$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		35		Ī	f = 1.0MHz, See Fig. 5
C <sub>oss</sub>	Output Capacitance		1920		ĺ	$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$
C <sub>oss</sub>	Output Capacitance		170		Ī	$V_{GS} = 0V, V_{DS} = 64V, f = 1.0MHz$
C <sub>oss</sub> eff.	Effective Output Capacitance		310		ĺ	$V_{GS} = 0V$ , $V_{DS} = 0V$ to 64V

#### **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			39		MOSFET symbol
	(Body Diode)				Α	showing the
I <sub>SM</sub>	Pulsed Source Current			150		integral reverse
	(Body Diode) ①					p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$ , $I_S = 23A$ , $V_{GS} = 0V$ ④
t <sub>rr</sub>	Reverse Recovery Time		75	110	ns	$T_J = 25^{\circ}C, I_F = 23A, V_{DD} = 25V$
Q <sub>rr</sub>	Reverse Recovery Charge		210	310	nC	di/dt = 100A/µs ④
t <sub>on</sub>	Forward Turn-On Time	Intrinsio	turn-or	time is	negligib	le (turn-on is dominated by LS+LD)

Notes ① through ⑧ are on page 11

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## International TOR Rectifier

## IRLR/U2908PbF

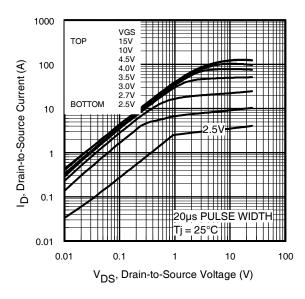


Fig 1. Typical Output Characteristics

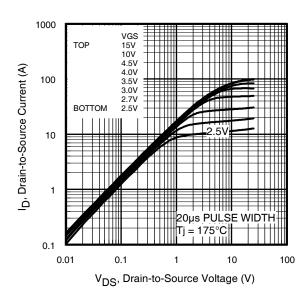


Fig 2. Typical Output Characteristics

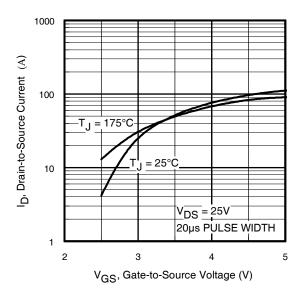


Fig 3. Typical Transfer Characteristics

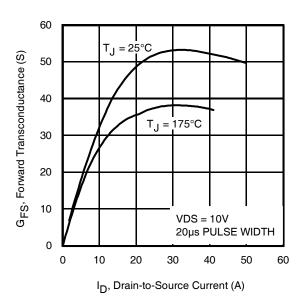
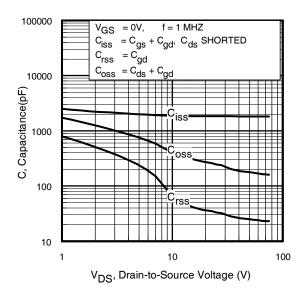
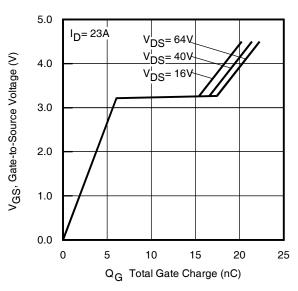


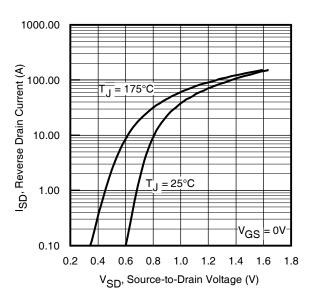
Fig 4. Typical Forward Transconductance vs. Drain Current



**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage

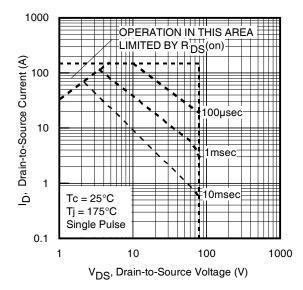
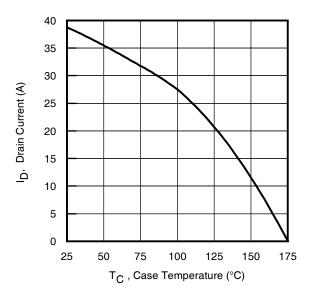


Fig 8. Maximum Safe Operating Area

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## IRLR/U2908PbF



**Fig 9.** Maximum Drain Current vs. Case Temperature

**Fig 10.** Normalized On-Resistance vs. Temperature

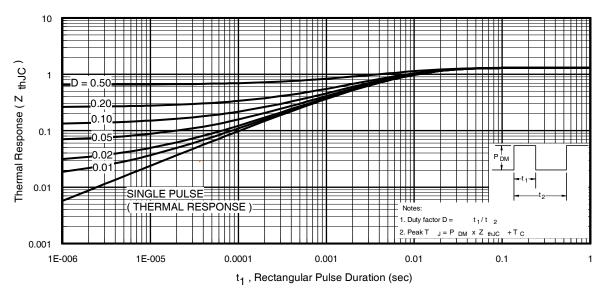


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

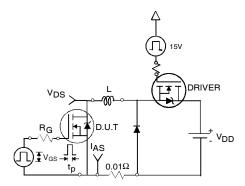


Fig 12a. Unclamped Inductive Test Circuit

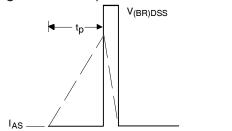


Fig 12b. | Unclamped Inductive Waveforms

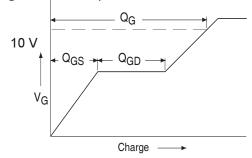
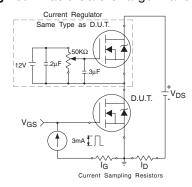


Fig 13a. Basic Gate Charge Waveform



**Fig 13b.** Gate Charge Test Circuit 6

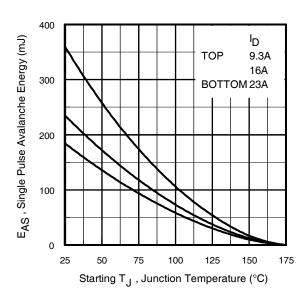
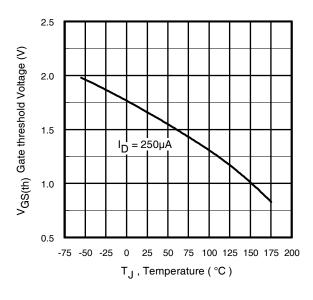


Fig 12c. Maximum Avalanche Energy vs. Drain Current



**Fig 14.** Threshold Voltage vs. Temperature www.irf.com

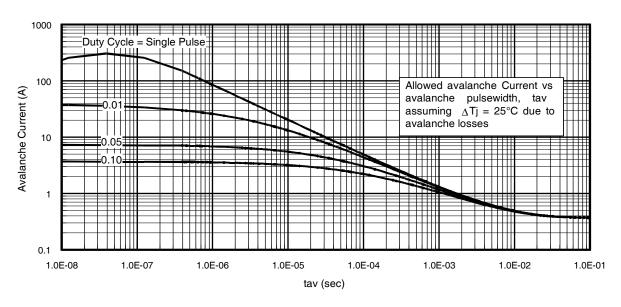


Fig 15. Typical Avalanche Current vs. Pulsewidth

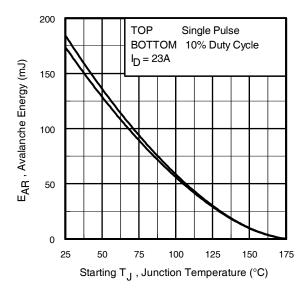


Fig 16. Maximum Avalanche Energy vs. Temperature

#### Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{imax}$ . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long  $asT_{jmax}$  is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed T<sub>imax</sub> (assumed as 25°C in Figure 15, 16).  $t_{av}$  = Average time in avalanche.

D = Duty cycle in avalanche =  $t_{av} \cdot f$ 

 $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see figure 11)

$$\begin{split} P_{D \text{ (ave)}} &= 1/2 \text{ ( } 1.3 \cdot \text{BV} \cdot I_{av} \text{)} = \triangle \text{T} / Z_{thJC} \\ I_{av} &= 2\triangle \text{T} / \left[ 1.3 \cdot \text{BV} \cdot Z_{th} \right] \\ E_{AS \text{ (AR)}} &= P_{D \text{ (ave)}} \cdot t_{av} \end{split}$$

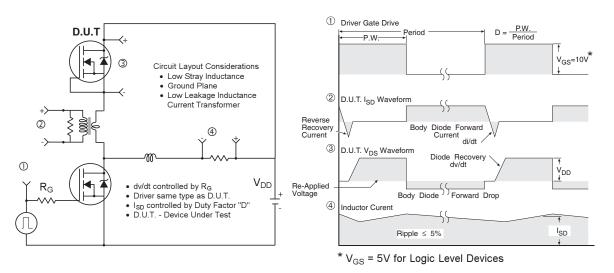


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

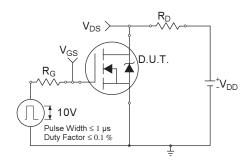


Fig 18a. Switching Time Test Circuit

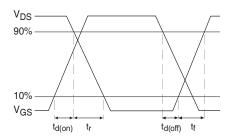


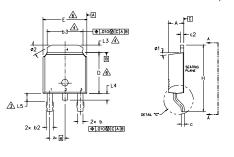
Fig 18b. Switching Time Waveforms

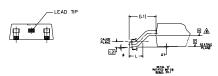
## International IOR Rectifier

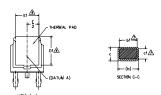
## IRLR/U2908PbF

## D-Pak (TO-252AA) Package Outline

Dimensions are shown in millimeters (inches)







- NOTES:

  1.— DIMENSIONING AND TOLERANCING PER ASME Y14.5M—1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- A- DIMENSION D1, E1, L3 & 63 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.— SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- DIMENSION b1 & c1 APPLIED TO BASE METAL ONLY.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S Y M		DIMEN	SIONS		Ŋ
B O	MILLIM	ETERS	INCHES		O T
L	MIN.	MAX,	MIN.	MAX.	E S
Α	2,18	2.39	.086	.094	
A1	-	0.13	-	,005	
ь	0.64	0.89	.025	.035	
ь1	0.65	0.79	.025	.031	7
b2	0.76	1,14	.030	.045	
b3	4,95	5.46	.195	.215	4
c	0.46	0.61	.018	.024	
c1	0.41	0.56	.016	.022	7
c2	0.46	0.89	.018	.035	
D	5,97	6.22	.235	.245	6
D1	5.21	-	.205	-	4
Ε	6.35	6.73	.250	.265	6
E1	4.32	-	.170	-	4
е	2.29	BSC	.090	BSC	
Н	9.40	10,41	.370	,410	
L	1,40	1,78	.055	,070	
L1	2.74	BSC	.108	REF.	
L2	0.51	BSC	.020	BSC	
L3	0,89	1,27	.035	,050	4
L4	-	1,02	-	.040	
L5	1,14	1.52	.045	.060	3
ø	0.	10*	0*	10"	
ø1	0.	15*	0,	15*	
Ф2	25*	35*	25*	35*	

#### LEAD ASSIGNMENTS

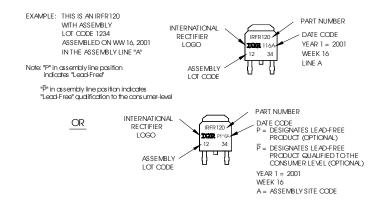
#### <u>HEXFET</u>

- 1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN

## IGBT & CoPAK

- 1.- GATE
  2.- COLLECTOR
  3.- EMITTER
  4.- COLLECTOR

## D-Pak (TO-252AA) Part Marking Information



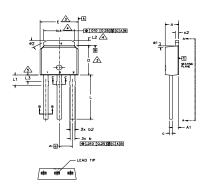
- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

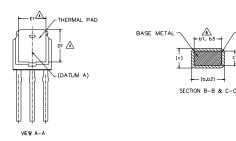
## IRLR/U2908PbF



## I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)





#### NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- ⚠ DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1.
- A- LEAD DIMENSION UNCONTROLLED IN L3.
- A- DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.
- 7.- DUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA (Date 06/02).
- 8.- CONTROLLING DIMENSION : INCHES.

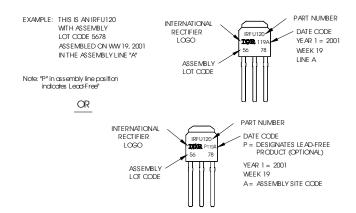
S	S Y DIMENSIONS				
B 0	MILLIM	ETERS	INCHES		N O T E S
L	MIN.	MAX.	MIN.	MAX.	S
Α	2,18	2.39	.086	.094	
A1	0.89	1,14	.035	.045	
b	0.64	0.89	.025	.035	
b1	0,65	0.79	.025	,031	6
b2	0.76	1,14	.030	.045	
ь3	0,76	1,04	.030	,041	6
b4	4,95	5,46	.195	.215	4
С	0.46	0.61	.018	.024	
c1	0,41	0.56	.016	.022	6
c2	0,46	0.89	,018	.035	
D	5.97	6.22	.235	.245	3
D1	5.21	-	.205	-	4
Ε	6,35	6.73	.250	.265	3
E1	4,32	-	,170	-	4
е	2,29	2,29 BSC		.090 BSC	
L	8.89	9.65	.350	.380	
L1	1,91	2.29	.045	.090	
L2	0,89	1.27	.035	.050	4
L3	1,14	1.52	.045	,060	5
ø1	0,	15"	0+	15*	
ø2	25*	35*	25*	35*	

#### LEAD ASSIGNMENTS

HEXFET

1.- GATE
2.- DRAIN
3.- SOURCE
4.- DRAIN

## I-Pak (TO-251AA) Part Marking Information



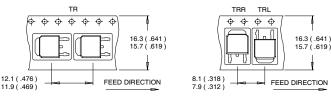
#### Notes:

- 1. For an Automotive Qualified version of this part please see <a href="http://www.irf.com/product-info/auto/">http://www.irf.com/product-info/auto/</a>
- 2. For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

## IRLR/U2908PbF

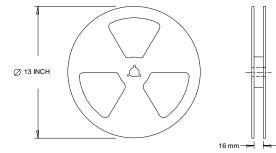
#### D-Pak (TO-252AA) Tape & Reel Information

Dimensions are shown in millimeters (inches)



#### NOTES

- 1. CONTROLLING DIMENSION: MILLIMETER.
  2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
  3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES : 1. OUTLINE CONFORMS TO EIA-481.

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by  $T_{Jmax}$ , starting  $T_{J} = 25^{\circ}C$ , L = 0.71mH,  $R_{G} = 25\Omega$ ,  $I_{AS} = 23A$ ,  $V_{GS} = 10V$ . Part not recommended for use above
- $\exists \ I_{SD} \leq 23A, \ di/dt \leq 400A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_{J} \leq 175^{\circ}C.$
- 4 Pulse width  $\leq$  1.0ms; duty cycle  $\leq$  2%.
- $\odot$  C<sub>oss</sub> eff. is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>.
- 6 Limited by T<sub>Jmax</sub>, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- This value determined from sample failure population. 100% tested to this value in production.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.



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